

Reasons For Allowance

The following is an examiner's statement of reasons for allowance: While the closest prior art of Wang (US Pub. 2003/0044652) and Iida (US PN 5,085,926) teach a layer system, they fail to teach hypostoichiometric layers within the lower and upper dielectric layer systems in combination with the other layers and specifically in the orientation claimed. The prior art does not provide motivation or teaching to modify the references to remedy this deficiency.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Any inquiry concerning this communication or earlier communications from the examiner should be directed to LAUREN ROBINSON whose telephone number is (571)270-3474. The examiner can normally be reached on Monday to Thursday 6am to 4pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Jennifer McNeil can be reached on 571-272-1540. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/LAUREN ROBINSON/
Examiner, Art Unit 1784

/Jennifer C. McNeil/
Supervisory Patent Examiner, Art Unit 1784